

3D NAND Flash

(BiCS5)

M.2 PCIe NVMe Module

HERMES-PA Series

(2242/2280 Form-factor)

(Gen-III x 4)

Document No.: 100-xBMDP-JPAT5

Version No.: 01V0

Date: December, 2024

ISO 9001 : 2015 CERTIFIED













The images only for reference.



Product Features

■ Flash IC

- BiCS FLASH™.*4
- BiCS**5** 3D-NAND Flash.

■ Compatibility

- NVM Express[™] 1.4 Standard.
- PCI Express® Base Specification Rev 3.1

■ Additional Capabilities

- S.M.A.R.T.*¹ (Self-Monitoring, Analysis and Reporting Technology) feature set support.
- Static and Dynamic wear-leveling algorithm.
- Hardware Low Density Parity Check Code, LDPC support.
- End to End Data Path Protection
- Hybrid Write Mode with SLC Cache Enable
- Thermal Throttling Supported.

■ Mechanical

- PCI Gen3 x 4 NVMe interface(2280)
- M.2 keying notches in **M** positions.
- M.2 2242/2280-D2-M placement
- Dimension:
- **2280:** 80.0 mm x 22.0 mm
- **2242:** 42.0 mm x 22.0 mm

■ Power

- Operating Voltage 3.3V(+/-) 5%
- Read Mode: 3.9W (RMS.)
- Write Mode: 4.0W (RMS.)
- Idle Mode: 0.6W (RMS.)

■ Performance (512GB Maximum value) 2,3

- Sequential Read: 3,530.0 MB/sec. (1TB)
- Sequential Write: 2,840.0 MB/sec. (1TB)
- 4KB Random Read (IOPS.): 534.0K (1TB)
- 4KB Random Write (IOPS.): 337.0K (1TB)

■ Capacity

- **2242:** 128GB, 256GB, 512GB, 1TB
- **2280:** 128GB, 256GB, 512GB, 1TB, 2TB

■ Reliability

- **TBW:** Up to 3,080 TBW at 2TB Capacity. (Client workload by JESD-219A)
- ECC: Designed with hardware LDPC ECC engine with hard-decision and soft-decision decoding.
- **MTBF:** >3,000,000
- **Temperature:** (Operating)

Standard Grade: 0°C ~ +70°C

Wide Temp. Grade: -40°C ~ +85°C

- Vibration: 7 Hz~2K Hz/20G.
- **Shock:** 0.5ms, 1500 G, 3 axes

■ Certifications and Declarations

- Certifications: CE & FCC
- Declarations: RoHS & REACH

Remarks:

- 1. Support official S.M.A.R.T. Utility.
- Typical I/O performance using IOmeter with a queue depth of 32 (Standard grade)
- Sequential performance is based on CrystalDiskMark6.0.2 with file size 1000MB (Standard grade)
- 4. **BiCS** means Bit Cost Scalable Technology.
 - **BiCS FLASH** is a trademark of Toshiba Corporation.



Order Information

I. Part Number List

◆ APRO 3D NAND TLC M.2-2242 Form-factor PCIe NVMe Module HERMES-PA Series

Product Picture	Grade	Standard grade	Wide Temp Grade
Product Picture		(0°C ~ 70°C)	(-40°C ~ +85°C)
· G proces (Corp.) (The corp.)	128GB	SBMDP128G-JPAT54M	WBMDP128G-JPAT54M-C
	256GB	SBMDP256G-JPAT54M	WBMDP256G-JPAT54M-C
	512GB	SBMDP512G-JPAT54M	WBMDP511G-JPAT54M-C
நிற்ற வகுகிக்கிக்கிக்கிக்கிக்கிக்கிக்கிக்கிக்கி	1TB	SBMDP001T-JPAT54M	WBMDP001T-JPAT54M-C

◆ APRO 3D NAND TLC M.2-2280 Form-factor PCIe NVMe Module HERMES-PA Series

Product Picture	Grade	Standard grade	Wide Temp Grade
Product Picture		(0°C ~ 70°C)	(-40°C ~ +85°C)
	128GB	SBMDP128G-JPAT58M	WBMDP128G-JPAT58M-C
	256GB	SBMDP256G-JPAT58M	WBMDP256G-JPAT58M-C
	512GB	SBMDP512G-JPAT58M	WBMDP511G-JPAT58M-C
	1TB	SBMDP001T-JPAT58M	WBMDP001T-JPAT58M-C
	2ТВ	SBMDP002T-JPAT58M	WBMDP002T-JPAT58M-C

II. Part Number Decoder:

X1 X2 X3 X4 X5 X6 X7 X8 X9-X11 X12 X13 X14 X15 X16 X17-X19

X1 : Grade

S: Standard Grade – operating temp. 0° C ~ 70 ° C

W: Wide Temp Grade- operating temp. -40° C \sim +85 ° C

X2: The material of case

B: Bare PCBA w/o Casing

X3 X4 X5 : Product category

MDP: M.2 PCIe NVMe Module

X6 X7 X8 X9 : Capacity

128GB: 128GB **001T:** 1TB **256GB:** 256GB **002T:** 2TB

512GB: 512GB

X11 : Controller

J: HERMES Series

X12 X13 : Controller version

PA: HERMES-PA Series

X14 : Flash IC

T: KIOXIA NAND Flash IC

X15 : Flash IC grade / Type

5: BiCS5 3D-NAND Flash IC.

X16 X17: Form-Factor

4: 2242 Type

8: 2280 Type

M: with the notches in M positions

X19 : Reserved for specific requirement

C: Conformal coating (Optional)



Revision History

Revision	Description	Date
1.0	Initial release.	2024/12/31



Contents

Pro	duct F	Features 2 -
Ord	er Ini	formation 3 -
	I.	Part Number List 3 -
	II.	Part Number Decoder: 3 -
Rev	ision	History 4 -
Con	tents	5 5 -
1.		Introduction 6 -
	1.1.	. Scope 7 -
	1.2.	. Flash Management Technology – Static & Dynamic Wear Leveling 7 -
	1.3.	Bad Block Management7 -
	1.4.	End to End Data Path Protection7 -
	1.5.	. Thermal Management7 -
2.		Product Specifications 8 -
	2.1.	System Environmental Specifications 8 -
	2.2.	System Power Requirements 8 -
	2.3.	. Capacity and Device Parameters 8 -
	2.4.	System Performance 9 -
	2.5.	System Reliability9 -
	2.6.	. Physical Specifications 10 -
	2.7.	. Conformal coating 11 -
	2.8.	. Heat Sink copper layer 12 -
3.		Interface Description 12 -
	4.1.	. M.2 PCIe NVMe Module HERMES-PA Series interface 12 -
	4.2.	Pin Assignments 13 -
	4.3.	Electrical connectors of M.2 14 -
	4.4.	. Driver 14 -
Δni	endi	ix Δ· Limited Warranty - 15 -



1. Introduction

APRO 3D NAND TLC PCIe NVMe Module HERMES-PA Series provides high-capacity flash memory Solid State Drive (SSD) that electrically complies with NVM ExpressTM 1.3 Standard and support PCI Gen3 \times 4 NVMe interface with high performance.

The HERMES-PA Series M.2 2242/2280 SSD available disk capacities are 128GB, 256GB, 512GB, 1TB, 2TB (2280). Standard temperature range is from 0°C to +70°C with an optional wide temperature range from -40°C to +85°C. APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series comes with M positions, supports PCIe Gen III x 4 and it is compliant with NVM 1.4 providing excellent top and sustained performance.

APRO's HERMES-PA Series 3D NAND TLC M.2 PCIe NVMe 2242/2280 SSD provides the ultra-high random speed but in low power consumption. It is the most favorable solution for heavy-loading embedded systems or server computing with space limitation. The data transfer performance of 4K random read is 534,000 IOPS and the 4K random write is up to 337,000 IOPS; the sequential read is up to 3,530 MB/sec, and the sequential write is up to 2,840 MB/sec. test by a 1TB capacity 2242/2280 M.2 SSD.

The powerful controller provides LDPC (Low Density Parity Check) to detect eventual errors while writing and increases the reliability in comparison to a standard ECC mechanism.

APRO's sophisticated S.M.A.R.T. tool is available for customers' request. It can monitor the health status of the HERMES-PA Series 3D NAND TLC PCIe NVMe Module. The optional product with "Thermal Sensor" function, the user may detect its operating temperature by the S.M.A.R.T. tool whenever the SSD is operating. Currently, the S.M.A.R.T. tool is only for Windows OS based systems.

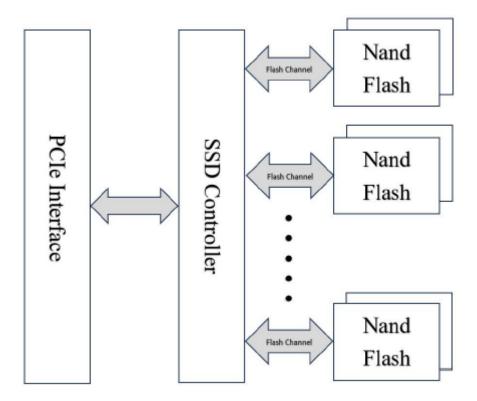


Figure 1: APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series block diagram



1.1. *Scope*

This document describes features, specifications and installation guide of APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series. In the appendix, there provides order information, warranty policy, RMA/DOA procedure for the most convenient reference.

1.2. Flash Management Technology - Static & Dynamic Wear Leveling

NAND flash devices can only undergo a limited number of program/erase cycles, and in most cases, the flash media are not used evenly. If some areas get updated more frequently than others, the lifetime of the device would be reduced significantly. Thus, Wear Leveling is applied to extend the lifespan of NAND Flash by evenly distributing write and erase cycles across the media.

APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series provides advanced Wear Leveling algorithm, which can efficiently spread out the flash usage through the whole flash media area. Moreover, by implementing both wear-leveling algorithms, the life expectancy of the NAND flash are greatly improved, as dynamic and also static data is shifted, if necessary, in order to guarantee an evenly use of all flash cells.

1.3. Bad Block Management

Early Bad Block

The fault block generated during the manufacturing process of NAND Flash is called Early Bad Block.

> Later Bad Block

In the process of use, as the number of operations of writing and erasing increases, a fault block is gradually generated, which is called a Later Bad Block.

Bad block management is a management mechanism for a bad block to be detected by the control IC and mark bad blocks in the NAND Flash and improve the reliability of data access. The bad block management mechanism of the control IC will establish a **Bad Block Table** when the NAND Flash is started for the first time, and will also record the errors found in the process of use in the bad block table, and data is ported to new valid blocks to avoid data loss.

In order to detect the initial bad blocks to handle run time bad blocks, APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series provides the **Bad Block Management** scheme. It remaps a bad block to one of the reserved blocks so that the data contained in one bad block is not lost and new data writes on a bad block is avoided.

1.4. End to End Data Path Protection

End-to-end Data Path Protection that secures the data transmission between host system and NAND Flash. In the transmission path, no matter in or out, all buffer and storage implement Error Code Correction that optimizes the data integrity in the whole transmission of SSD.

1.5. Thermal Management

APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series has built-in thermal sensor which can detect environment temperature of SSD. In the meantime, firmware will monitor the thermal sensor to prevent any failure of overheating. During extreme temperature, firmware will adjust the data transfer behavior to maintain the SSD's reliable operation.



2. Product Specifications

For all the following specifications, values are defined at ambient temperature and nominal supply voltage unless otherwise stated.

2.1. System Environmental Specifications

Table 1: Environmental Specification

APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series		Standard Grade Wide Temp Grade			
_ Operating:		0°C ~ +70°C	-40°C ~ +85°C		
Temperature	Non-operating:	-20°C ~ +80°C	-50°C ~ +95°C		
Humidity	Operating & Non-operating:	10% ~ 95% non-condensing			
	Frequency/Acceleration:	7 Hz to 2K Hz, 20G, 3 axes (IEC 68-2-6)			
Shock	Operating & Non-operating:	0.5ms, 1500 G, 3 axes (IEC 68-2-27)			
	Temperature:	24°C			
Electrostatic	Relative Humidity:	51%			
Discharge (ESD)	I / AVVI	Device functions are affected, but EUT will be back to its normal or			
	+/-4KV:	operational state automatically.			

2.2. System Power Requirements

Table 2: Power Requirement

APRO 3D NAND TLC M.2-2280 Form-factor PCIe NVMe HERMES-PA Series						
DC Input Voltage 3.3V±5% (VCC) Idle Read Write						
	128GB	210	415	545		
M:	256GB	200	485	630		
Maximum average value	512GB	210	675	675		
(Unit: mA)	1ТВ	205	715	740		
	2ТВ	205	740	720		

Note: * Current results may vary depending on system components and power circuit design.

2.3. Capacity and Device Parameters

Capacity	LBA
128GB	250,069,680
256GB	500,118,192
512GB	1,000,215,216
1ТВ	2,000,409,264
2ТВ	4,000,797,360



2.4. System Performance

Table 3: System Performances

Data Transfer Mode supporting		PCI Gen3 x 4 NVMe interface		
Form-factor		2242/2280		
	Conneiler	Sequential Read	Sequential Write	
Capacity		(MB/sec.)	(MB/sec.)	
Maximum	128GB	1500	940	
Performance	256GB	3,000	1,740	
	512GB	3,550	2,820	
	1TB	3,530	2,840	
	2TB	3,210	2,810	

Note:

- > Performance results are measured in Room Temperature with Out-of-Box devices and may vary depending on overall system setup. In addition, HERMES-PA Series adopt hybrid mode which enables SLC Cache up to 3% of total user capacity followed by TLC direct write to strike balance between burst performance and steady overall stability.
- > Performance results are based on CrystalDiskMark 6.0.2 with file size 1000MB. Unit of 4KB items is I.O.P.S.
- > Performance results are based on AIDA 64 v5.98 with block size 1MB of Linear Read & Write Test Item.

2.5. System Reliability

Table 4: System Reliability

, ,			
Wear-leveling Algorithms Stat		Static and Dynamic wear-leveling algorithms	
Bad Block Mana	gement	Supportive	
ECC Technology		Hardware design LDPC (Low Density Parity Check)	
Erase counts		NAND 3D NAND TLC Flash Cell Level : 3K P/E Cycles	
TBW (Tera Bytes	s Written)	Client workload (TB)	
128GB		192	
	256GB	385	
Capacity	512GB	770	
1ТВ	1TB	1,540	
2TB		3,080	

Note:

- > Sequential: Mainly sequential write are estimated by PassMark Burnin Test v8.1 pro.
- > Client: Follow JESD218 Test method and JESD219A Workload, tested by ULINK. (The capacity lower than 64GB client workload is not specified in JEDEC219A, the values are estimated.)
- > Based on out-of-box performance.



2.6. Physical Specifications

Refer to Table 5 and see Figure 2 for 3D NAND TLC M.2-2242&2280 Form-factor PCIe NVMe Module HERMES-PA Series physical specifications and dimensions.

 Form-factor
 2242
 2280

 Length:
 42.0 mm
 80.0 mm

 Width:
 22.0 mm
 22.0 mm

 Weight:
 4.5g (max.)
 8.0g (max.)

Table 5: Physical Specifications

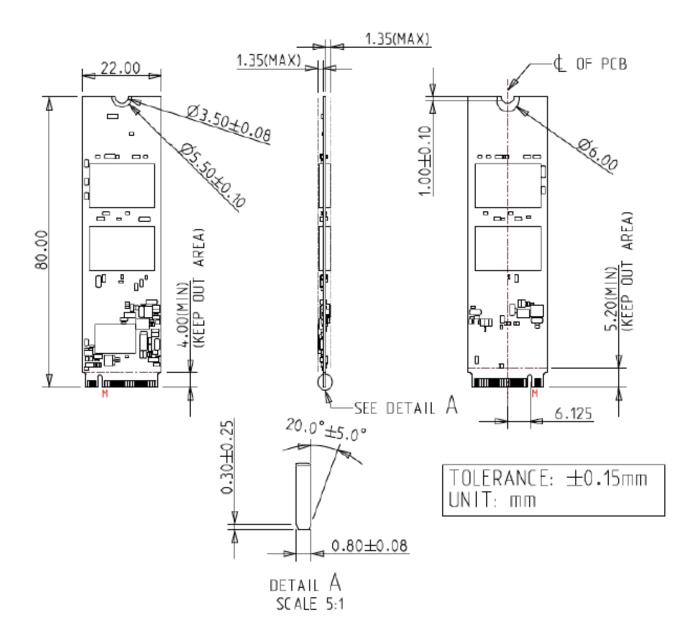


Figure 2-1: APRO 3D NAND TLC M.2-2280 Form-factor PCIe NVMe Module HERMES-PA Series

w/o Heat Sink Dimension



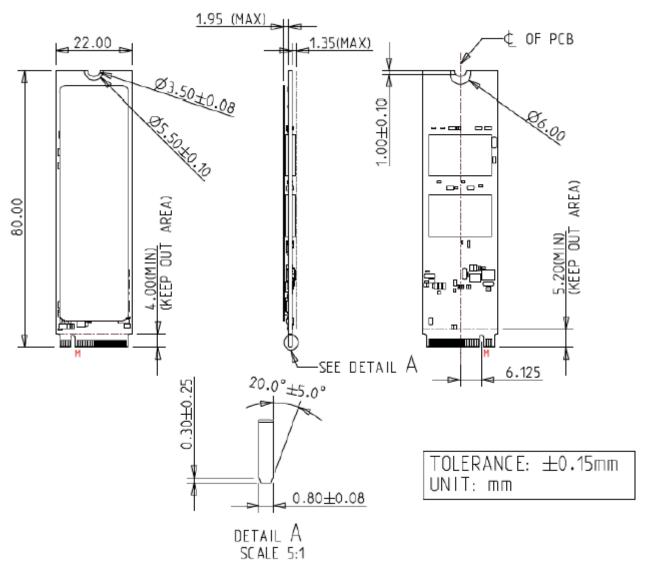


Figure 2-2: APRO 3D NAND TLC M.2-2280 Form-factor PCIe NVMe Module HERMES-PA Series

W/Heat Sink Dimension

2.7. Conformal coating

Conformal coating is a protective, dielectric coating designed to conform to the surface of an assembled printed circuit board. Commonly used conformal coatings include silicone, acrylic, urethane and epoxy. APRO applies only silicone on APRO storages products upon requested especially by customers. The type of silicone coating features good thermal shock resistance due to flexibility. It is also easy to apply and repair.

Conformal coating offers protection of circuitry from moisture, fungus, dust and corrosion caused by extreme environments. It also prevents damage from those Flash storages handling during construction, installation and use, and reduces mechanical stress on components and protects from thermal shock. The greatest advantage of conformal coating is to allow greater component density due to increased dielectric strength between conductors.

APRO use MIL-I-46058C silicon conformal coating

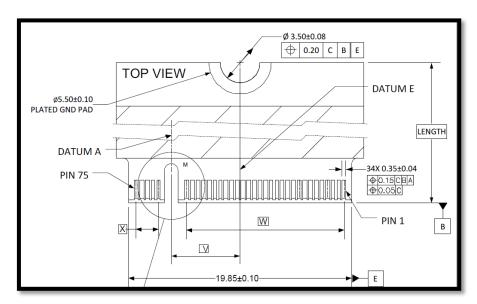


2.8. Heat Sink copper layer

APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series industrial temperature models come with a Heat Sink copper layer installed on top of M.2 PCIe NVMe SSD with dimension of 68x20x0.25 mm. This design will increase M.2 PCIe NVMe SSD height to 1.95mm max due to the thermal pad and copper layer itself.

3. Interface Description

4.1. M.2 PCIe NVMe Module HERMES-PA Series interface



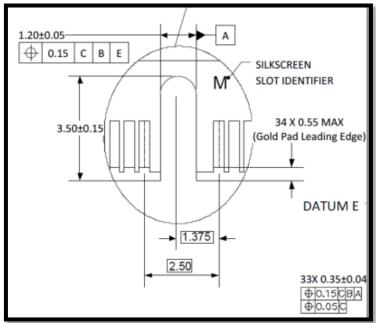


Figure 3: The connectors of Signal Segment and Power Segment



4.2. Pin Assignments

APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series follows standard M.2 spec, socket 3 key M PCIe-based SSD pinout.

Table 6 - Pin Assignments

		<u> </u>	_		<u></u>
Pin#	Name	Description	Pin#	Name	Description
1	GND	Config_3=Ground	2	3.3V	3.3 Source
3	GND	Ground	4	3.3V	3.3 Source
5	PETn3	PCIe TX Differential	6	N/C	No connect
7	PETp3	PCIe TX Differential	8	N/C	No connect
9	GND	Ground	10	DAS/DSS (O)	Device Activity Signal /
9	GND	Ground	10	DAS/DSS (0)	Disable Staggered Spinup
11	PERn3	PCIe RX Differential	12	3.3V	3.3 Source
13	PERp3	PCIe RX Differential	14	3.3V	3.3 Source
15	GND	Ground	16	3.3V	3.3 Source
17	PETn2	PCIe TX Differential	18	3.3V	3.3 Source
19	PETp2	PCIe TX Differential	20	N/C	No connect
21	GND	Config_0=Ground	22	N/C	No connect
23	PERn2	PCIe RX Differential	24	N/C	No connect
25	PERp2	PCIe RX Differential	26	N/C	No connect
27	GND	Ground	28	N/C	No connect
29	PETn1	PCIe TX Differential	30	N/C	No connect
31	PETp1	PCIe TX Differential	32	N/C	No connect
33	GND	Ground	34	N/C	No connect
35	PERn1	PCIe RX Differential	36	N/C	No connect
37	PERp1	PCIe RX Differential	38	N/C	No connect
39	GND	Ground	40	N/C	No connect
41	PETn0	PCIe TX Differential	42	N/C	No connect
43	PETp0	PCIe TX Differential	44	N/C	No connect
45	GND	Ground	46	N/C	No connect
47	PERn0	PCIe RX Differential	48	N/C	No connect
40	DED=0	DCIa DV Differential	F0	PERST#(I)	DCI a recet
49	PERp0	PCIe RX Differential	50	(0/3.3V)	PCIe reset
51	GND	Ground	52	CLKREQ#(I/O)	Reference clock request
21	טווט	Ground	52	(0/3.3V)	signal
		PCIe Reference Clock EFCLKn signals (100 MHz)		PEWAKE#(I/O) (0/3.3V)	PCIe PME Wake.
53	REFCLKn		54		Open Drain with pull up on
		Signais (100 MHz)			platform; Active Low.
55	REFCLKp	PCIe Reference Clock signals	56	MEG1	Reserved for SSD
33	KLICLKP	(100 MHz)	56 MFG1	manufacturing only. Pins	



					should be left N/C in platform Socket.
57	GND	Ground	58	MFG2	Reserved for SSD manufacturing only. Pins should be left N/C in platform Socket
59	Module key M		60	Module key M	
61	Module key M	Madula kay	62	Module key M	Modulo kov
63	Module key M	Module key	64	Module key M	Module key
65	Module key M		66	Module key M	
67	N/C	No Connect	68	SUSCLK (I)(0/3.3V)	32.768kHz clock supply input that is provided by the platform chipset
69	PEDET (NC-PCIe)	Config_1=No Connect	70	3.3V	3.3 Source
71	GND	Ground	72	3.3V	3.3 Source
73	GND	Ground	74	3.3V	3.3 Source
75	GND	Config_2=Ground			

4.3. Electrical connectors of M.2

APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series interconnection is based on a 75 positions Edge Card connector. The 75 positions connector is intended to be keyed so as to distinguish between families of host interfaces and the various Sockets used in general Platforms.

APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series follows standard M.2 spec, socket 3 key M PCIe-based SSD pinout

4.4. Driver

APRO 3D NAND TLC M.2 PCIe NVMe Module HERMES-PA Series is compliant with NVM Express™ 1.4 Standard.

The application's O.S. and BIOS should include NVMe driver to compatible with NVMe storage device. Most of O.S. includes NVMe in-box driver now.

O.S. Driver: Please visit the website http:/nvmexpress.org/resources/drivers for more information about the driver for each O.S **BIOS Driver:** NVMe driver for BIOS support, please contact with motherboard manufacturers.



Appendix A: Limited Warranty

APRO warrants your 3D NAND TLC M.2-2242 & 2280 Form-factor PCIe NVMe Module HERMES-PA Series against defects in material and workmanship for the life of the drive. The warranty is void in the case of misuse, accident, alteration, improper installation, misapplication or the result of unauthorized service or repair. The implied warranties of merchantability and fitness for a particular purpose, and all other warranties, expressed or implied, except as set forth in this warranty, shall not apply to the products delivered. In no event shall APRO be liable for any lost profits, lost savings or other incidental or consequential damages arising out of the use of, or inability to use, this product.

BEFORE RETURNING PRODUCT, A RETURN MATERIAL AUTHORIZATION (RMA) MUST BE OBTAINED FROM APRO.

Product shall be returned to APRO with shipping prepaid. If the product fails to conform based on customers' purchasing orders, APRO will reimburse customers for the transportation charges incurred.

WARRANTY PERIOD:

3D NAND TLC (Standard grade / Wide temp. grade) 2 years / Within 3K Erasing Counts

This document is for information use only and is **subject to change without prior notice**. APRO Co., Ltd. assumes no responsibility for any errors that may appear in this document, nor for incidental or consequential damages resulting from the furnishing, performance or use of this material. No part of this document may be reproduced, transmitted, transcribed, stored in a retrievable manner or translated into any language or computer language, in any form or by any means, electronic, mechanical, magnetic, optical, chemical, manual or otherwise, without the prior written consent of an officer of APRO Co., Ltd.

All parts of the APRO documentation are protected by copyright law and all rights are reserved.

APRO and the APRO logo are registered trademarks of APRO Co., Ltd.

Product names mentioned herein are for identification purposes only and may be trademarks and/or registered trademarks of their respective companies.

© 2024 APRO Corporation. All rights reserved